

[METHODS AND APPARATUS FOR DEFECT ISOLATION]

Abstract

In a first aspect, a first method is provided for isolating a defect in a scan chain. The first method includes the steps of (1) modifying a first test mode of one or more of a plurality of latches included in the scan chain; (2) operating the one or more latches whose first test modes are modified in the modified first test mode; and (3) operating one or more of the plurality of latches included in the scan chain in a second test mode. Numerous other aspects are provided.